

**Search Notes**

Application/Control No.

10/026,618

Examiner

Emmanuel Bayard

Applicant(s)/Patent under  
Reexamination

LEE ET AL.

Art Unit

2611

**SEARCHED**

Class	Subclass	Date	Examiner
375	316	11/9/2007	EB
375	326	11/9/2007	EB
375	327	11/9/2007	EB
375	340	11/9/2007	EB
375	324	11/9/2007	EB
375	344	11/9/2007	EB
375	345	11/9/2007	EB
375	354	11/9/2007	EB

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
375	354	11/9/2007	EB
375	316	11/9/2007	EB

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	11/9/2007	EB